



1.SCOPE

This specification is applied to a SAW resonator designer for the stabilization of transmitters such as garage door openers and security transmitters.

2.ELECTRICAL

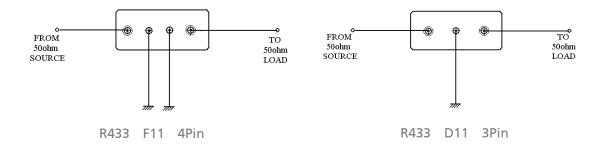
2.1 Maximum Rating

| DC Voltage VDC | 10 V | | |
|-----------------------|------------------|--|--|
| AC Voltage Vpp | 10V 50Hz/60Hz | | |
| Operation temperature | -40 °C to +85 °C | | |
| Storage temperature | -40 ℃ to +85℃ | | |
| Max Input Power | 10 dBm | | |

2.2 Electronic Characteristics

| Item | | | Unites | Minimum | Typical | Maximum |
|----------------------------------|-------------------------|---------------------|----------------------|---------|---------|---------|
| Center Frequency | | | MHz | 433.845 | 433.920 | 433.995 |
| Insertion Loss | | | dB | | 1.6 | 2.2 |
| Quality Factor | | Unload Q | | 8300 | 12000 | |
| | | 50Ω Loaded Q | | 850 | 1500 | |
| Temperature Stability | Turnover Temperature | | °C | 10 | 25 | 40 |
| | Freq.temp.Coefficient | | ppm/ °C ² | | 0.032 | |
| Frequency Aging | | | ppm/ yr | | < ± 10 | |
| DC. Insulation Resistance | | | MΩ | 1.0 | | |
| RF Equivalent RLC Model | Motional Resistance R1 | | Ω | | 18 | 26 |
| | Motional Inductance L1 | | μH | | 79.82 | |
| | Motional Capacitance C1 | | fF | | 1.685 | |
| Transducer Static Capacitance C0 | | | pF | | 2.3 | |

3. TEST CIRCUIT



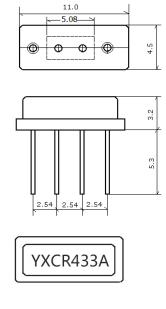
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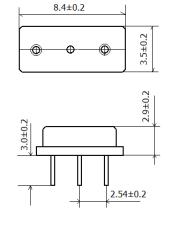
R433 F11 D11



4. DIMENSION



R433 F11 4Pin





R433 D11 3Pin

5. ENVIRONMENTAL CHARACTERISTICS

5-1 High temperature exposure

Subject the device to $+85^{\circ}$ C for 16 hours. Then release the resonator into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

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R433 F11 D11



5-2 Low temperature exposure

Subject the device to -40° C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2.2.

5-3 Temperature cycling

Subject the device to a low temperature of -40° C for 30 minutes. Following by a high temperature of $+85^{\circ}$ C for 30 minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2.2.

5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at $260^{\circ}C \pm 10^{\circ}C$ for 10 ± 1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2.2.

5-5 Solderability

Subject the device terminals into the solder bath at $245^{\circ}C \pm 5^{\circ}C$ for 5s , More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2.2.

5-6 Mechanical shock

Drop the device randomly onto the concrete floor the height of 1m 3 times. the device shall fulfill the specifications in 2.2.

5-7 Vibration

Subject the device to the vibration for 1 hour each in x, y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2.2.

6. REMARK

6.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.

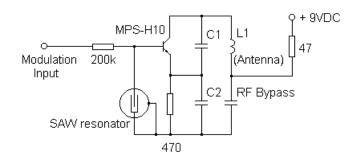
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7. TYPCIAL APPLICATION CIRCUITS

Typical low-power Transmitter Application



Typical Local Oscillator Application

